



## Description

### JMT N And P-Channel Enhancement Mode MOSFET

#### Features

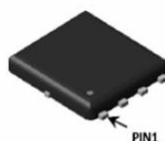
- N-Channel: 40V, 16A  
 $R_{DS(ON)} < 20m\Omega @ V_{GS} = 10V$   
 $R_{DS(ON)} < 29m\Omega @ V_{GS} = 4.5V$
- P-Channel: -40V, -16A  
 $R_{DS(ON)} < 50m\Omega @ V_{GS} = -10V$   
 $R_{DS(ON)} < 65m\Omega @ V_{GS} = -4.5V$
- Excellent Gate Charge x  $R_{DS(ON)}$  Product(FOM)
- Very Low On-resistance  $R_{DS(ON)}$
- Fast Switching Speed

#### Application

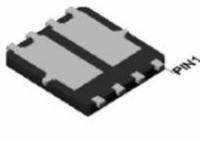
- Battery Protection
- Load Switch
- Power Management



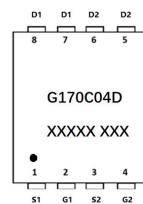
100% UIS TESTED!  
100%  $\Delta V_{ds}$  TESTED!



Top View

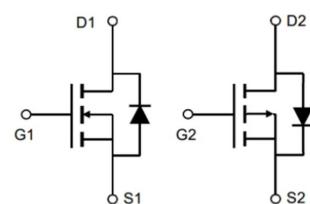


Bottom View



PDFN5x6-8L-D

Marking and pin Assignment



Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	Outline	Package	Reel Size	Reel (pcs)	Per Carton (pcs)
G170C04D	JMTG170C04D	TAPING	PDFN5x6-8L-D	13"	2500	25000

## Absolute Maximum Ratings ( $T_C=25^\circ C$ unless otherwise specified)

Symbol	Parameter		Max. N-Channel	Max. P-Channel	Units
$V_{DSS}$	Drain-Source Voltage		40	-40	V
$V_{GSS}$	Gate-Source Voltage		$\pm 20$	$\pm 20$	V
$I_D$	Continuous Drain Current	$T_C = 25^\circ C$	16	-16	A
		$T_C = 100^\circ C$	10	-10	A
$I_{DM}$	Pulsed Drain Current <sup>note1</sup>		64	-64	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>note2</sup>		30	42	mJ
$P_D$	Power Dissipation	$T_C = 25^\circ C$	9.6	22	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		13	5.7	$^\circ C/W$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +150		$^\circ C$

**N-Channel Electrical Characteristics** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	40	-	-	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=40\text{V}$ , $V_{GS}=0\text{V}$	-	-	1.0	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS}=0\text{V}$ , $V_{GS}=\pm 20\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$	1.0	1.5	2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS}=10\text{V}$ , $I_D=15\text{A}$	-	16	20	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$ , $I_D=10\text{A}$	-	22	29	$\text{m}\Omega$
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS}=20\text{V}$ , $V_{GS}=0\text{V}$ , $f=1.0\text{MHz}$	-	980	-	pF
$C_{oss}$	Output Capacitance		-	86.2	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	68.5	-	pF
$Q_g$	Total Gate Charge	$V_{DD}=20\text{V}$ , $I_D=8\text{A}$ , $V_{GS}=10\text{V}$	-	11	-	nC
$Q_{gs}$	Gate-Source Charge		-	1.9	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	2.2	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=20\text{V}$ , $I_D= 16\text{A}$ , $V_{GS}=10\text{V}$ , $R_{REN} = 3\Omega$	-	11	-	ns
$t_r$	Turn-on Rise Time		-	13	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	36	-	ns
$t_f$	Turn-off Fall Time		-	9	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_s$	Maximum Continuous Drain to Source Diode Forward Current	-	-	16	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	64	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$ , $I_s= 16\text{A}$	-	-0.8	-1.2	V
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=16\text{A}$ , $di/dt=100\text{A}/\mu\text{s}$	-	19	-	ns
$Q_{rr}$	Body Diode Reverse Recovery		-	11	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition :  $T_J=25^\circ\text{C}$ ,  $V_{DD}=20\text{V}$ ,  $V_{GS}=10\text{V}$ ,  $L=0.5\text{mH}$ ,  $R_g=25\Omega$ ,  $I_{AS}=11\text{A}$ 3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$ , Duty Cycle $\leq 2\%$

**P-Channel Electrical Characteristics** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

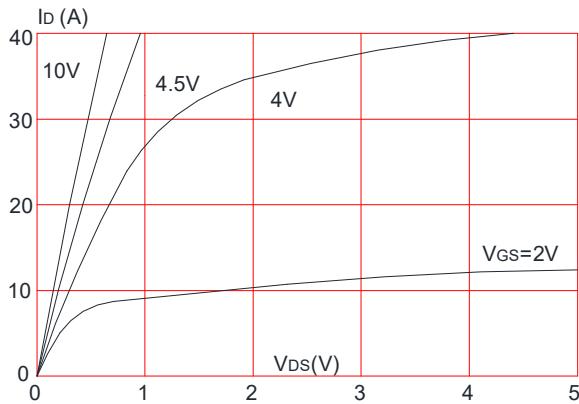
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D = -250\mu\text{A}$	-40	-	-	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS} = -40\text{V}$ , $V_{GS}=0\text{V}$	-	-	-1	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS}=0\text{V}$ , $V_{GS}= \pm 20\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D = -250\mu\text{A}$	-1.0	-1.6	-2.5	V
$R_{DS(\text{on})}$ note3	Static Drain-Source on-Resistance	$V_{GS} = -10\text{V}$ , $I_D = -8\text{A}$	-	40	50	$\text{m}\Omega$
		$V_{GS} = -4.5\text{V}$ , $I_D = -5\text{A}$	-	50	65	
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = -20\text{V}$ , $V_{GS}=0\text{V}$ , $f=1.0\text{MHz}$	-	1034	-	pF
$C_{oss}$	Output Capacitance		-	107	-	pF
$C_{rss}$	Reverse Transfer Capacitance		-	79.5	-	pF
$Q_g$	Total Gate Charge	$V_{DD} = -20\text{V}$ , $I_D = -8\text{A}$ , $V_{GS} = -10\text{V}$	-	20	-	nC
$Q_{gs}$	Gate-Source Charge		-	3.5	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	4.2	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = -20\text{V}$ , $I_D = -16\text{A}$ , $V_{GS} = -10\text{V}$ , $R_{\text{GEN}} = 2.5\Omega$	-	8	-	ns
$t_r$	Turn-on Rise Time		-	15	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	23	-	ns
$t_f$	Turn-off Fall Time		-	9	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_s$	Maximum Continuous Drain to Source Diode Forward Current	-	-	-16	-	A
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-64	-	A
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}$ , $I_s = -16\text{A}$	-	-0.8	-1.2	V
$trr$	Reverse Recovery Time	$I_F = -16\text{A}$ , $di/dt = 100\text{A}/\mu\text{s}$	-	29	-	ns
$Qrr$	Reverse Recovery Charge		-	20	-	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

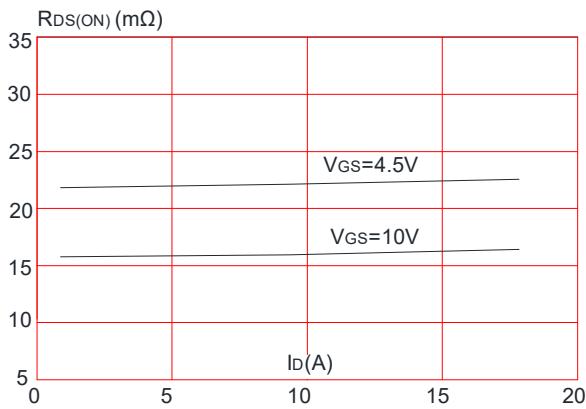
2. EAS condition : Starting  $T_J=25^\circ\text{C}$ ,  $V_{DD}=-20\text{V}$ ,  $V_{GS}=-10\text{V}$ ,  $L=0.5\text{mH}$ ,  $R_g=25\Omega$ ,  $I_{AS}=-13\text{A}$ 3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$ , Duty Cycle $\leq 2\%$

## Typical Performance Characteristics-N

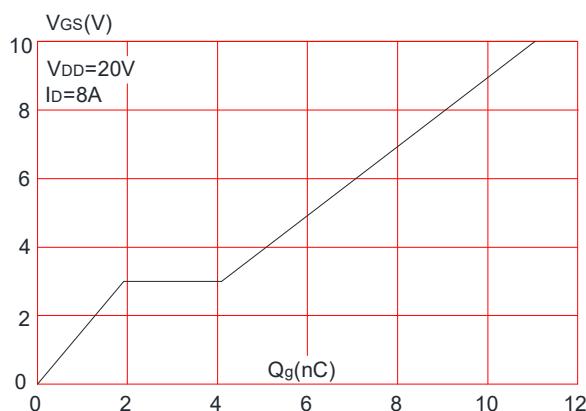
**Figure 1:** Output Characteristics



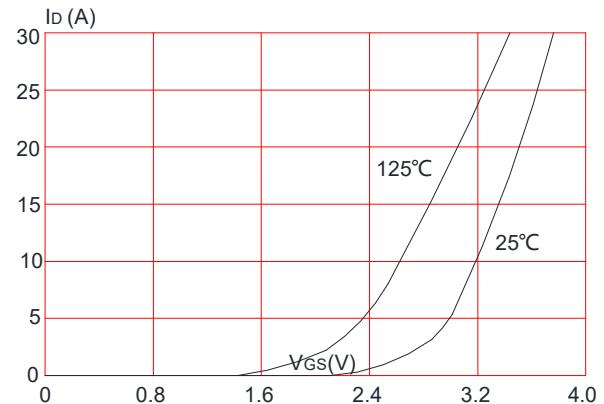
**Figure 3:** On-resistance vs. Drain Current



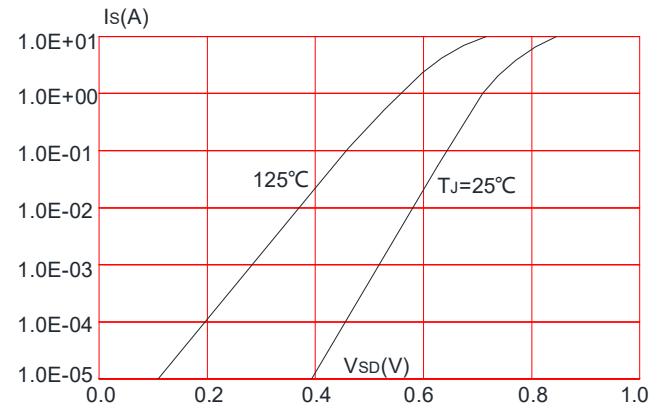
**Figure 5:** Gate Charge Characteristics



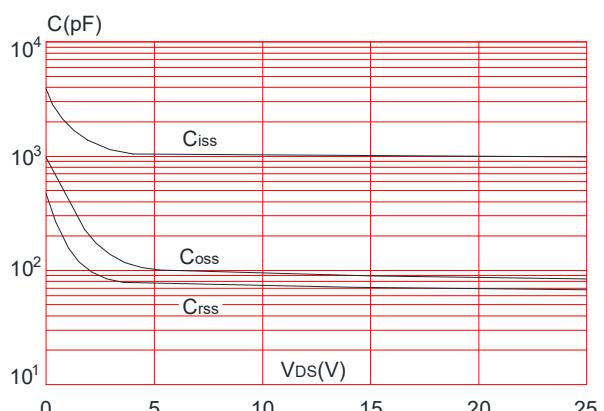
**Figure 2:** Typical Transfer Characteristics



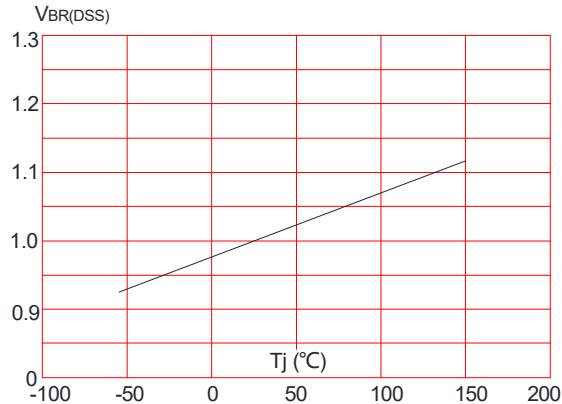
**Figure 4:** Body Diode Characteristics



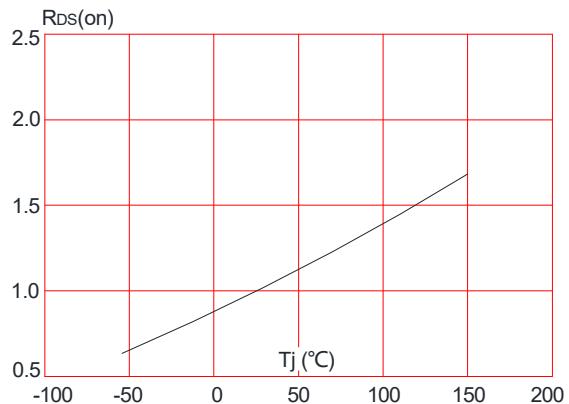
**Figure 6:** Capacitance Characteristics



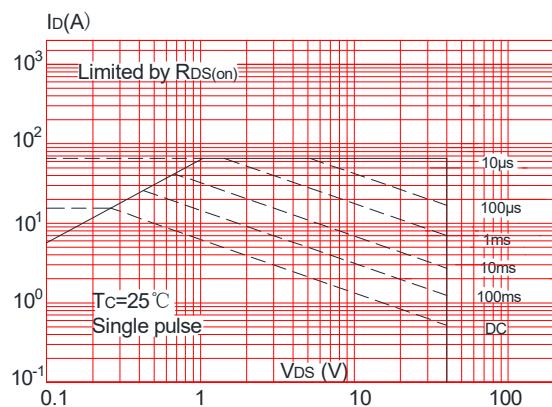
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



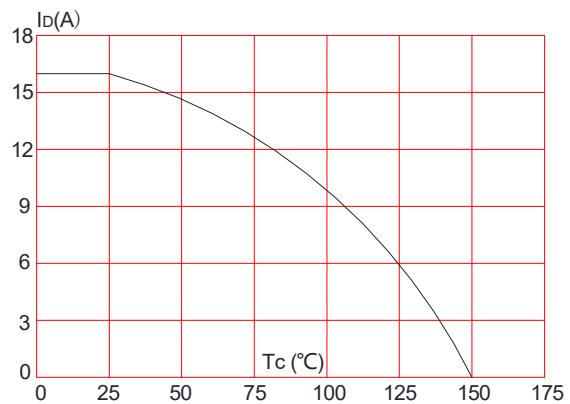
**Figure 8:** Normalized on Resistance vs. Junction Temperature



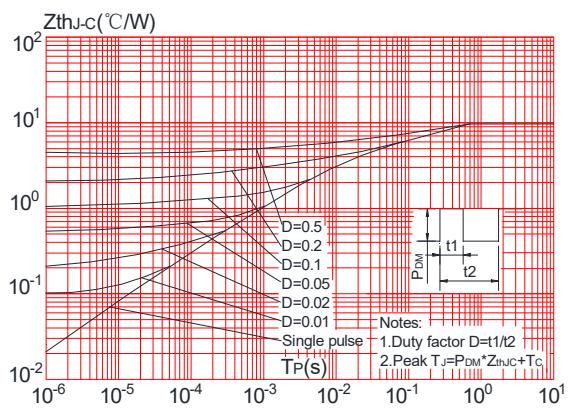
**Figure 9:** Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



## Test Circuit-N

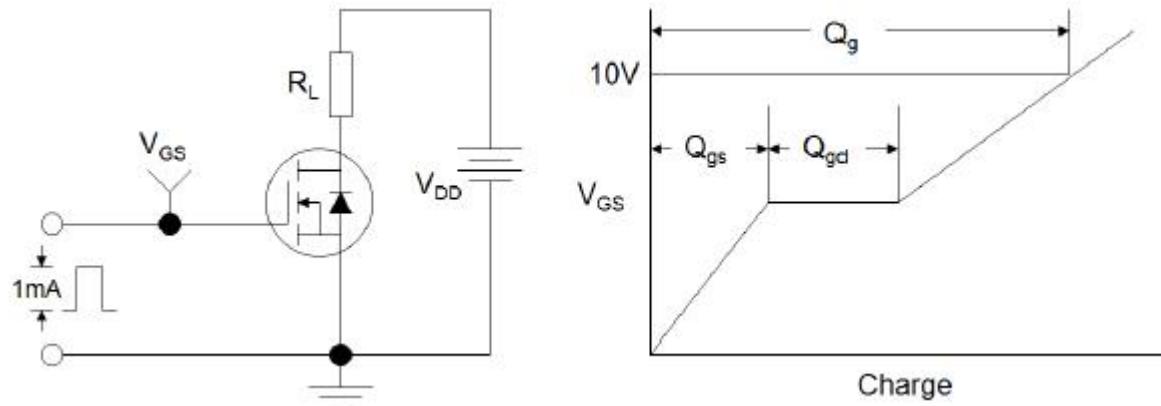


Figure1:Gate Charge Test Circuit & Waveform

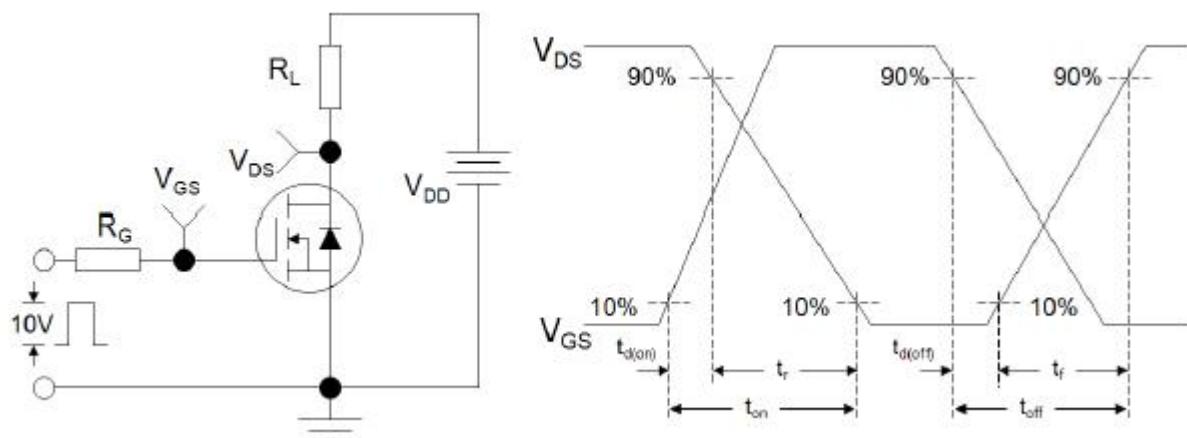


Figure 2: Resistive Switching Test Circuit & Waveforms

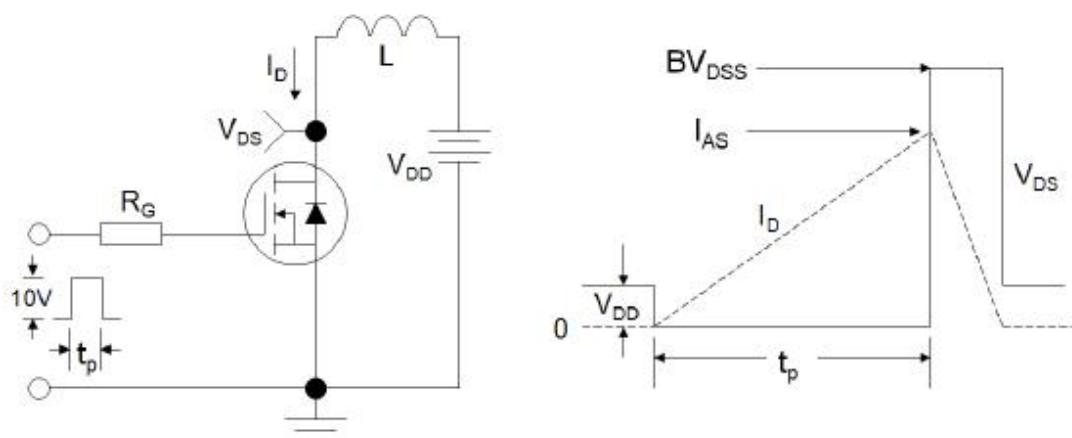
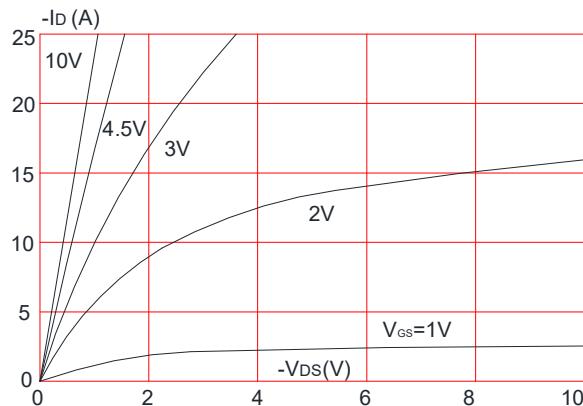


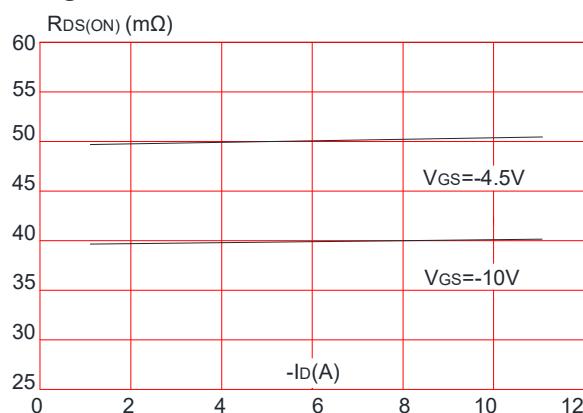
Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

## Typical Performance Characteristics-P

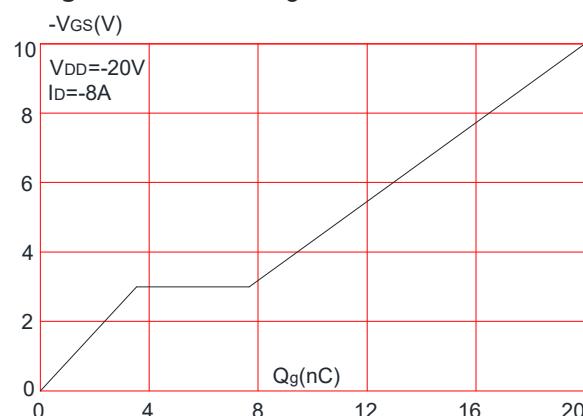
**Figure 1:** Output Characteristics



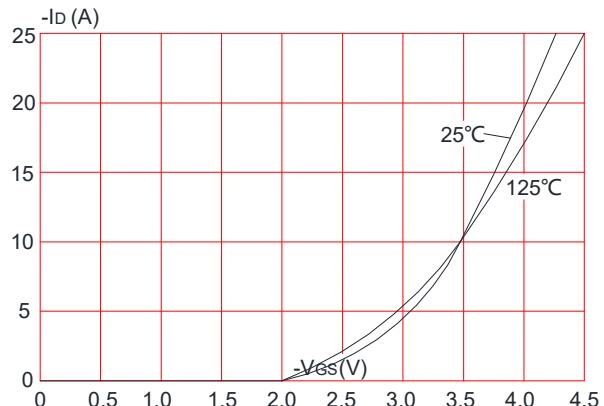
**Figure 3:** On-resistance vs. Drain Current



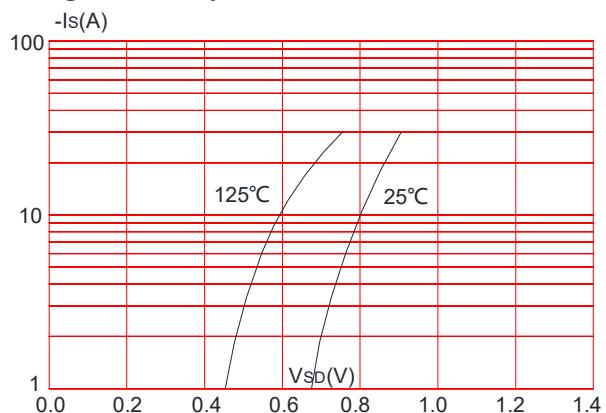
**Figure 5: Gate Charge Characteristics**



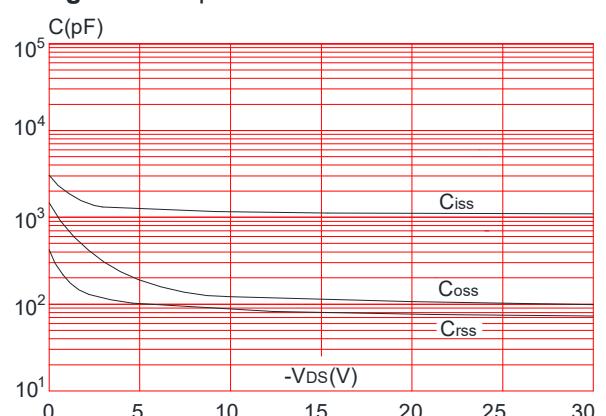
**Figure 2:** Typical Transfer Characteristics



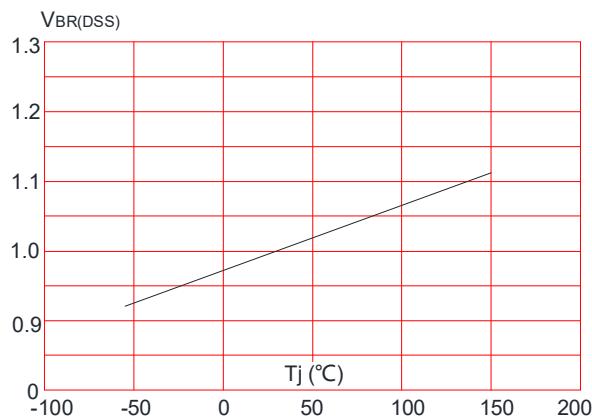
**Figure 4:** Body Diode Characteristics



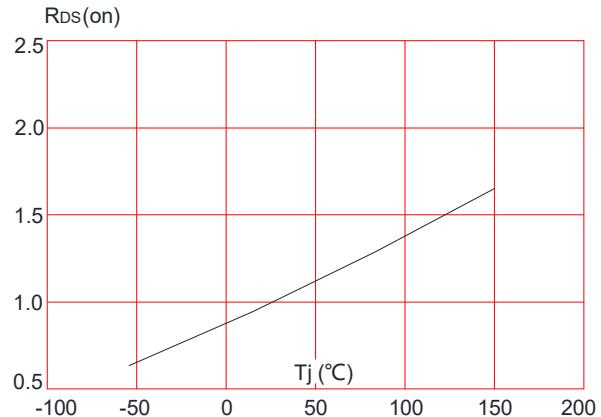
**Figure 6: Capacitance Characteristics**



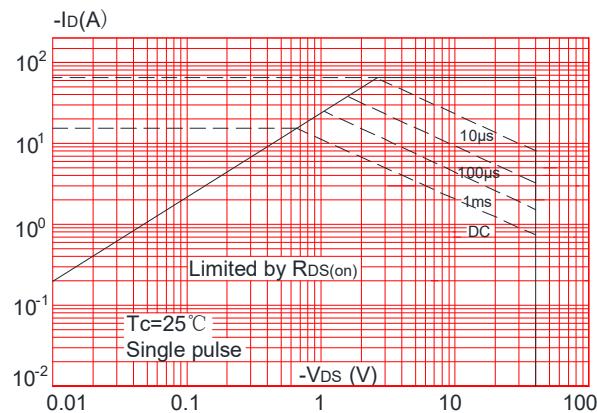
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



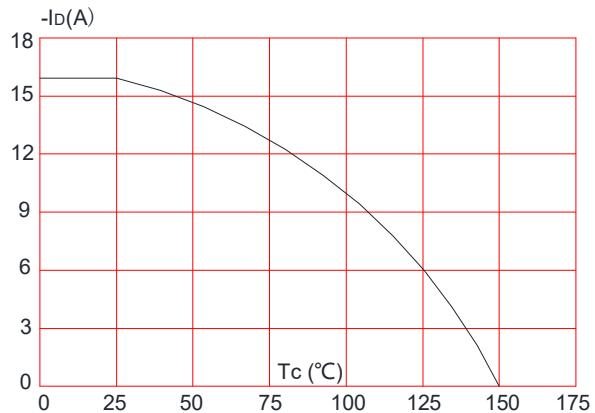
**Figure 8:** Normalized on Resistance vs. Junction Temperature



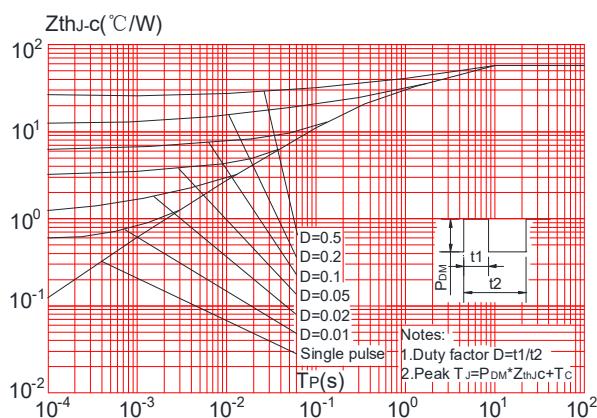
**Figure 9:** Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature

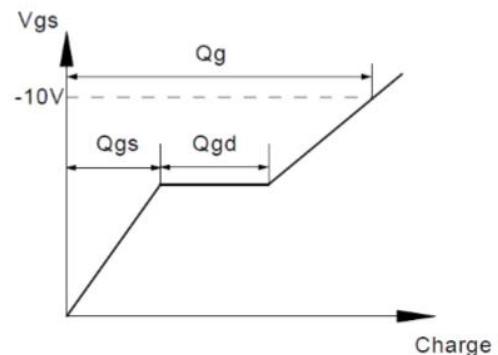
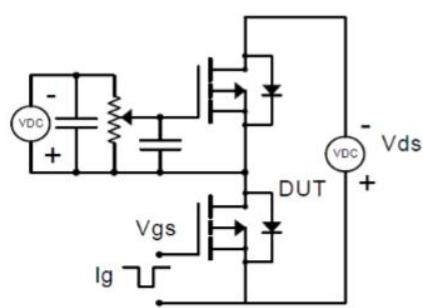


**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case

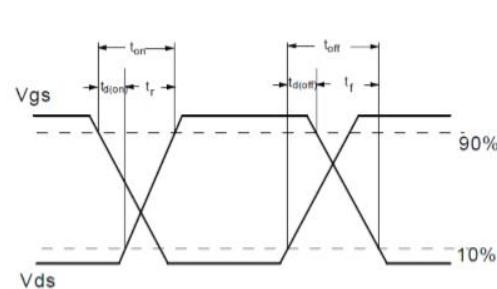
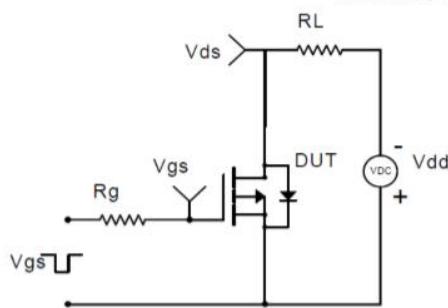


## Test Circuit-P

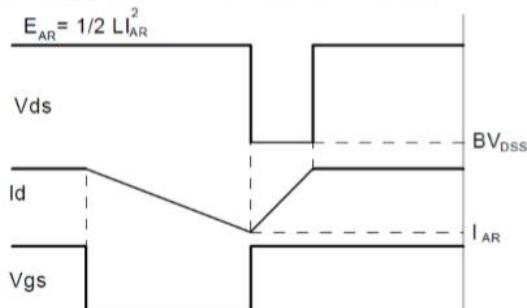
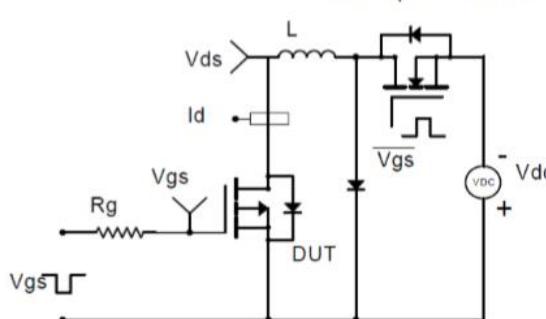
Gate Charge Test Circuit & Waveform



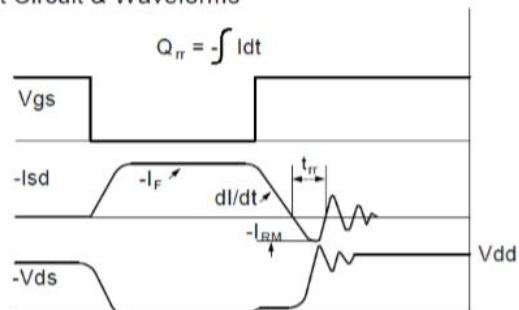
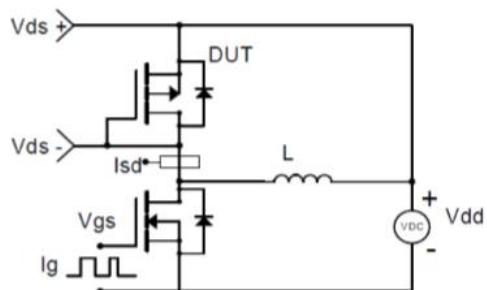
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

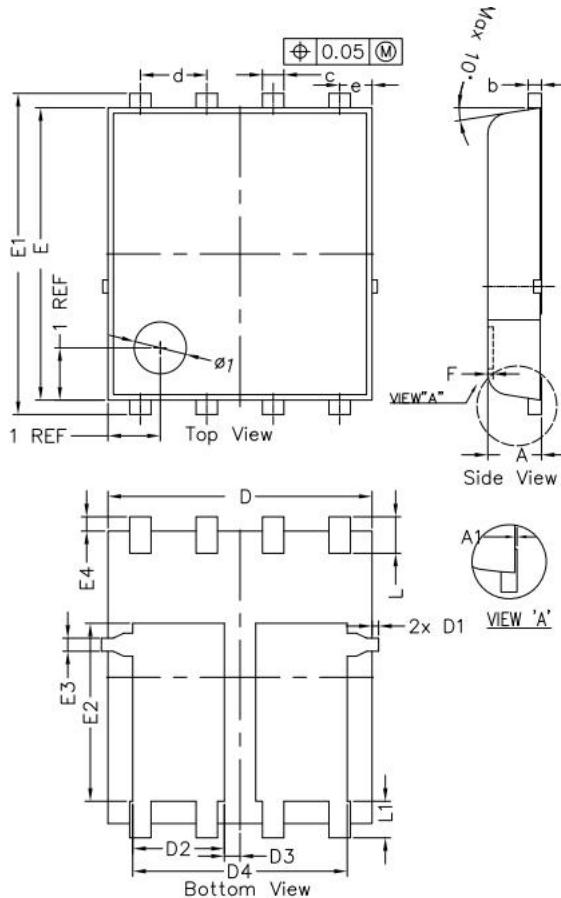


Diode Recovery Test Circuit & Waveforms





## Package Mechanical Data- PDFN5x6-8L-D



SYMBOLS	DIMENSION IN MM			DIMENSION IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
* A	0.900	1.000	1.100	0.035	0.039	0.043
A1	0.000	---	0.050	0.000	---	0.002
b	0.246	0.254	0.312	0.010	0.010	0.012
* c	0.310	0.410	0.510	0.012	0.016	0.020
d	1.27 BSC			0.050 BSC		
* D	4.950	5.050	5.150	0.195	0.199	0.203
* D1	---	---	0.125	---	---	0.005
* D2	1.650	1.750	1.850	0.065	0.069	0.073
D3	0.200	0.300	0.400	0.008	0.012	0.016
D4	4.000	4.100	4.200	0.157	0.161	0.165
e	0.62 BSC			0.024 BSC		
* E	5.500	5.600	5.700	0.217	0.220	0.224
* E1	6.050	6.150	6.250	0.238	0.242	0.246
E2	3.310	3.410	3.510	0.130	0.134	0.138
E3	0.150	0.250	0.350	0.006	0.010	0.014
* E4	0.175	0.275	0.375	0.007	0.011	0.015
F	-	-	0.100	-	-	0.004
* L	0.500	0.600	0.700	0.02	0.02	0.03
L1	0.600	0.700	0.800	0.02	0.03	0.03

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